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Edited by David B Williams and Ryuichi Shimizu

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Microbeam Analysis 2000

IUMAS President's Address

IUMAS 2000—the second conference of the International Union of Microbeam Analysis Societies—celebrates the ever-increasing international scope of microanalysis techniques using electron, ion and photon beams. IUMAS, founded in 1994, now comprises eight member organizations: the Australian Microbeam Analysis Society (AMAS), the Brazilian Society for Microscopy and Microanalysis (SBMM), the Microscopy Society of Canada (MSC), the China Joint Committee of Microbeam Analysis, the European Microbeam Analysis Society (EMAS), the Japan Society for the Promotion of Science (JSPS) Committee 141-Microbeam Analysis, the Korean Society for Electron Microscopy and the Microbeam Analysis Society (MAS) of the USA. Following the first AMAS-sponsored meeting in Sydney, Australia in 1996, this second meeting is co-sponsored by the Japanese and US Microbeam Analysis Societies, so the obvious locale is midway between the two countries, in Kailua-Kona, Hawaii, the site of the highly successful MAS meeting in 1987. This meeting promises to be even better, with more than 240 papers and participants from 22 countries, and we look forward enthusiastically to the third meeting in 2004.

The meeting would not have been possible without the financial support of many microscopy/microanalysis companies and organizations listed. These companies and local MAS organizations also helped sponsor ten students from Australia, USA and China to attend the meeting as well as providing help for many invited speakers.

I would also like to thank the other hard-working members of the program committee and local arrangements committee whose names are also listed in this section of the proceedings. Finally, Sharon Coe, the Conference Coordinator in the Materials Science and Engineering Department at Lehigh University, is the person on whom most of the organizational responsibility for the technical program fell. She should take all the credit for what promises to be a fine meeting. Any foul-ups in the technical program organization, the proceedings and program booklet are my responsibility alone. So enjoy the latest in advanced microanalysis techniques, along with the best social and recreational delights that Hawaii has to offer.

David B Williams

Countries represented

Australia, Austria, Belgium, Brasil, Canada, China, Czech Republic, France, Germany, Israel, Italy, Japan, Korea, Netherlands, Poland, Russia, Slovenia, Spain, Sweden, Thailand, UK, and USA.

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Previous IUMAS Conference

Sydney, Australia, 1996

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